

AMENDMENTS TO THE CLAIMS

1. (Currently Amended) A multi-bit test circuit for determining a match in logical level among a plurality of data bits read out in parallel from a memory array, comprising:

a plurality of first determining circuits, arranged corresponding to said plurality of data bits, each for receiving, as a pair, a corresponding data bit and a teacher data bit placed in a predetermined relation with said corresponding data bit in the plurality of data bits, and determining a match in logical level between received data bits, data bits in each pair including different teacher data bits from other pair(s), said plurality of data bits being divided into at least three groups, and the first determining circuits being arranged such that a data bit in a group of said at least three groups is compared with a data bit in each of other two groups, and the number of said plurality of first determining circuits being the same as the number of said plurality of data bits; and

a final determining circuit for outputting a final determination signal indicating a match in logical level among said plurality of data bits in accordance with output signals of said plurality of first determining circuits.

2. (Original) The multi-bit test circuit according to claim 1, wherein
said plurality of data bits are divided into a plurality of groups each having a predetermined number of data bits, and
each of said plurality of first determining circuits receives, as a teacher data bit thereof, a data bit in a different group from a corresponding group including a corresponding

data bit and in a same position in the different group as a position of the corresponding data bit in the corresponding group.

3. (Original) The multi-bit test circuit according to claim 1, wherein said plurality of data bits are applied in parallel, and divided into a plurality of groups each having a same data width, and each of said plurality of first determining circuits receives, as said teacher data bit, a data bit that is in a group adjacent to a corresponding group including a corresponding data bit and in a corresponding position in the adjacent group to a position of the corresponding data bit in the corresponding group.

Claim 4 (cancelled).

5. (Original) The multi-bit test circuit according to claim 3, wherein each of said plurality of first determining circuits receives, as said teacher data bit, a data bit in a corresponding position, to a position of a corresponding data bit, in a group adjacent in cyclic manner among said plurality of groups.

6. (Original) The multi-bit test circuit according to claim 1, wherein said plurality of data bits are applied in parallel, and divided into a plurality of groups having a same bit width; and said plurality of first determining circuits are arranged corresponding to said plurality of data bits, respectively, and receive, as teacher data bits, data bits in

corresponding positions, in groups different from the groups of corresponding data bits.

7. (Currently Amended) The multi-bit test circuit according to claim 1, wherein said plurality of data bits are applied in parallel, and are divided into a plurality of groups of a same bit width, and

said plurality of first determination circuits comprise a plurality of gate circuits, arranged corresponding to respective data bits of a predetermined number of groups of said plurality of groups, each for receiving a corresponding data bit and the teacher data bit represented by a data bit located in a corresponding position in a different group from a corresponding group including the corresponding data, ~~as the teacher data bit~~ and determining a match in logic level between the corresponding data bit and the received teacher data bit.

8. (Original) The multi-bit test circuit according to claim 1, further comprising a teacher signal transmission bus for transmitting expected value teacher data of plural bits, wherein

said plurality of data bits are applied in parallel, and divided into a plurality of groups each having a predetermined number of data bits; and

said teacher signal transmission bus has a same bit width as the groups of the data bits, and

said plurality of first determining circuits comprises:

a plurality of first determination gates, arranged corresponding to respective data bits in a predetermined number of groups of said plurality of groups of data bits, each receiving

a corresponding data bit and a data bit in a corresponding position in a group different from a group including the corresponding data bit as said teacher data bits; and

a plurality of second determination gates, arranged corresponding to the respective data bits in other groups, each receiving a corresponding data bit in a corresponding group and a corresponding expected value teacher data bit of said expected value teacher data of plural bits.

9. (Currently Amended) The multi-bit test circuit according to claim 1, wherein each of the data bits is received by the ~~each are coupled to a same number of the~~ first determining circuits ~~of said plurality of first determination circuits.~~

10. (Original) The multi-bit test circuit according to claim 1, wherein an interconnection layout of each data bit to a corresponding first determining circuit is so set that interconnection loads of all the data bits are substantially the same with each other.

Claims 11 and 12 (cancelled).